



2018

Electronic Design Innovation  
Conference & Exhibition

October 17-19 2018  
Santa Clara Convention Center  
Santa Clara, CA

# Designing and Measuring 100uOhm Power Rails

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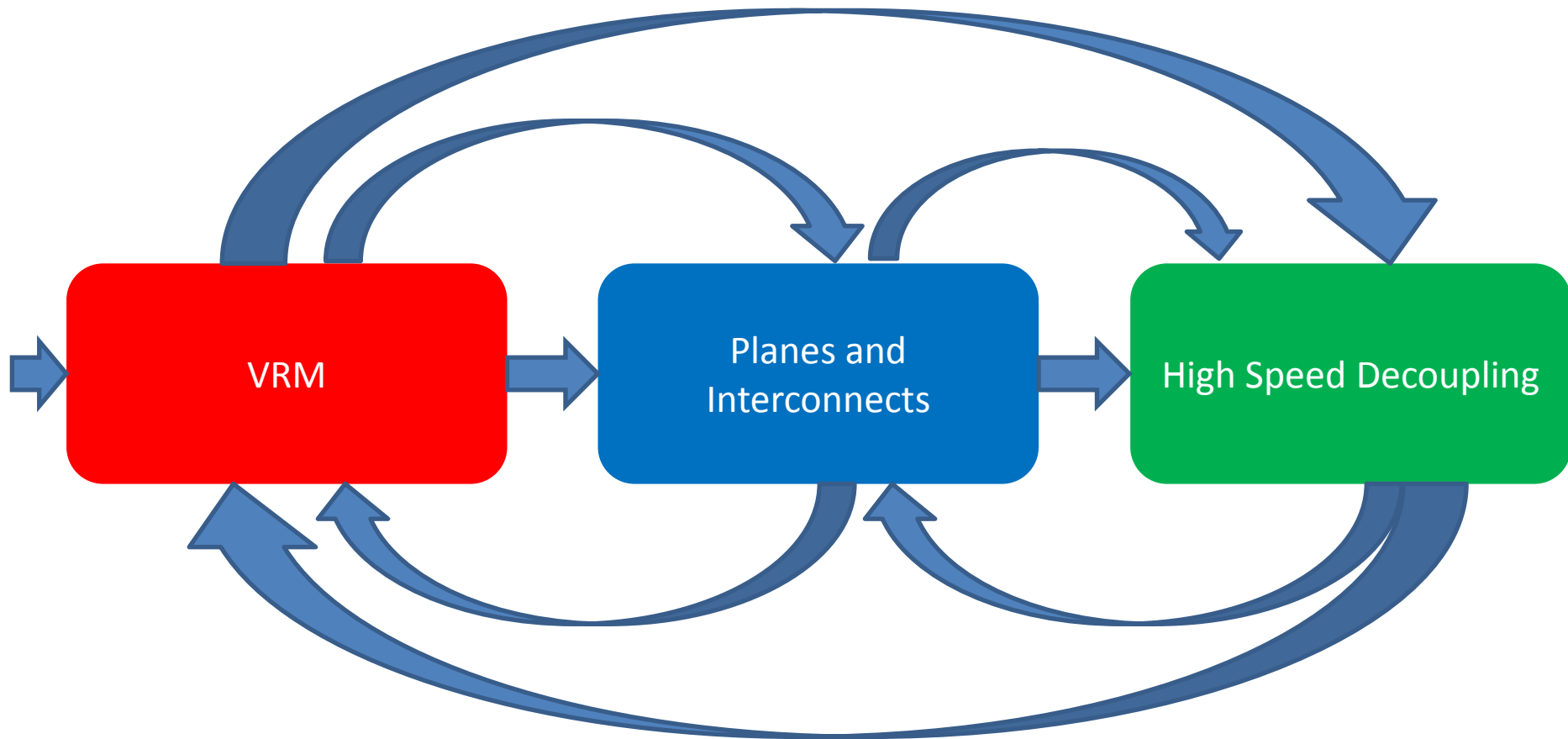
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$$\text{Rail Noise} = \sum \text{All noise sources}$$

$$\Delta V_{out} = \Delta V_{DC} + \Delta V_{Ripple} + \Delta I_{load} \cdot R_{target} + \frac{\Delta V_{in}}{PSRR}$$

$$R_{target} = \frac{\Delta V_{out} - \Delta V_{DC} - \Delta V_{Ripple} - \frac{\Delta V_{in}}{PSRR}}{\Delta I_{load}}$$

$$Z_{target}(f) = \frac{\Delta V_{out}(f) - \Delta V_{DC} - \Delta V_{Ripple}(f) - \frac{\Delta V_{in}(f)}{PSRR(f)}}{\Delta I_{load}(f)}$$

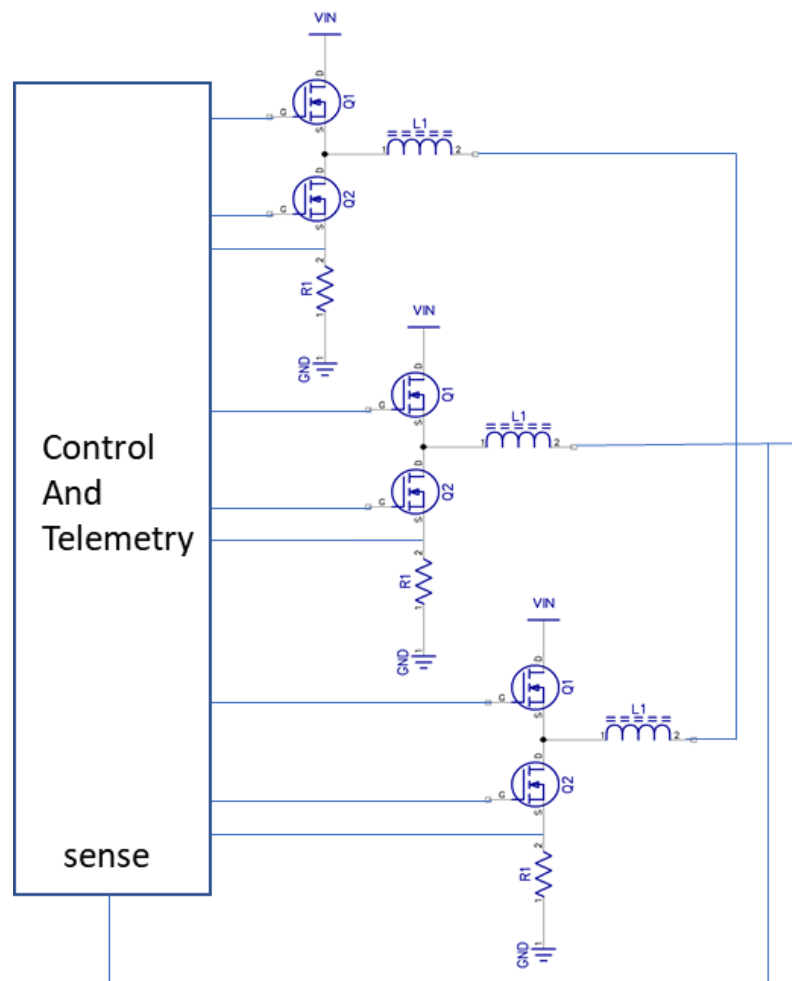
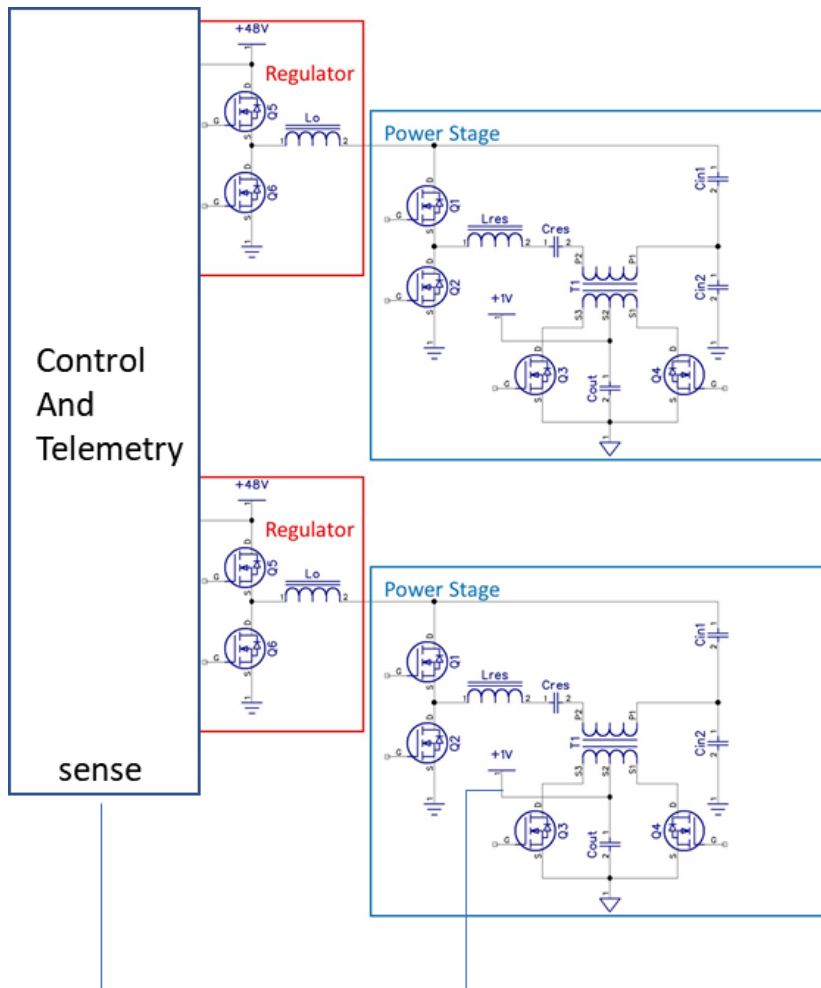
# Example

$$V_{rail} = 0.7VDC \quad I_{rail} = 500Amps$$

$$\Delta V_{rail} = \pm 50mV \quad \Delta I_{rail} = 250Amps$$

Noise Source		
DC setpoint accuracy	1%	1% * 700mV = 7mV
$\Delta V_{Ripple}$	1% pk	1% * 700mV = 7mV
$\Delta V_{in} * PSRR$	1% pk	1% * 700mV = 7mV
$\Delta I$	250Amps	
	Total other noise sources	$\pm 21mV$

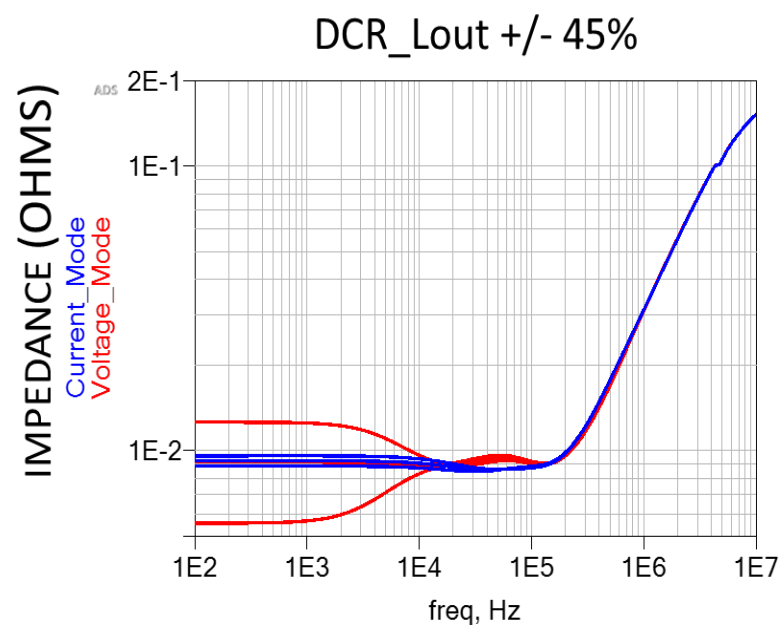
$$R_{target} = \frac{50mV - 7mV - 7mV - 7mV}{250A} = \frac{29mV}{250A} = 116\mu\Omega$$



$$R_{out} = \frac{\frac{2 \cdot F_s \cdot L_o \cdot R_i \cdot V_{in}}{R_i \cdot V_{in} - 2 \cdot R_i \cdot V_o + 2 \cdot F_{sw} \cdot L_o \cdot V_{ramp}} + DCR_{L_o} + RDSON_{bot} + (RDSON_{top} - RDSON_{bot}) \cdot \frac{V_o}{V_{in}}}{1 + A_v \cdot \frac{2 \cdot F_s \cdot L_o \cdot V_{in}}{R_i \cdot V_{in} - 2 \cdot R_i \cdot V_o + 2 \cdot F_{sw} \cdot L_o \cdot V_{ramp}}}$$

$$R_{out_{cm}} \approx \frac{R_i}{(1 + A_v)} = \frac{1}{PS_{gfs} \cdot (1 + A_v)}$$

Designation	
Lo	Output filter inductor of each regulator
Fs	Switching frequency
Ri	Current Sense resistance = $1/PS_{gfs}$
Vin	Voltage regulator DC input voltage
Vo	Voltage regulator output voltage
Vramp	Modulation or slope compensation ramp amplitude
Av	Feedback amplifier gain
N	Number of parallel switching regulators
K	Number of parallel current multiplier modules



$$L_{excess} = \frac{L_o}{1 + \frac{2 \cdot F_s \cdot L_o \cdot V_{in}}{R_i \cdot V_{in} - 2 \cdot R_i \cdot V_o + 2 \cdot F_s \cdot L_o \cdot V_{ramp}} \cdot A_v}$$

For Flat Impedance  $\longrightarrow$   $Q = \frac{\sqrt{\frac{L_{excess}}{C_{out}}}}{R_{out}} \approx 1$

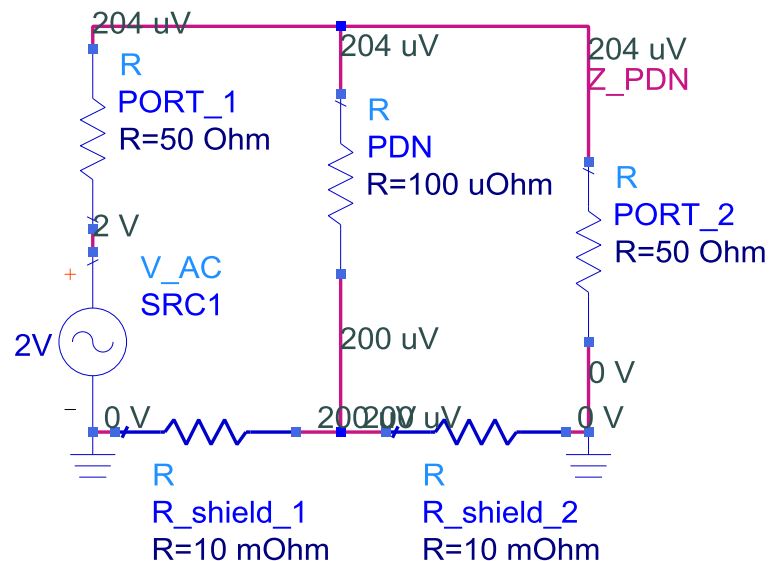
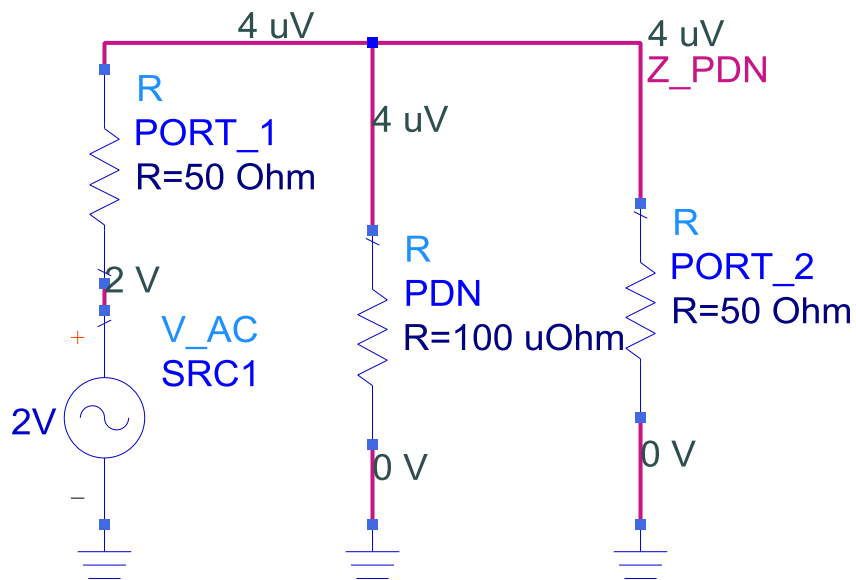
Solving for capacitance  $\longrightarrow$   $C_{out} \cong \frac{L_{excess}}{R_{out}^2}$

$$ESR_{C_{out}} \cong R_{out}$$

# Measurement Challenges at 100uΩ

$$S_{21} = \frac{DUT}{DUT + 25} = \frac{100\mu\Omega}{100\mu\Omega + 25} = 4\mu$$

$$DUT = \frac{25 \cdot S_{21}}{1 - S_{21}} = \frac{25 \cdot 4\mu}{1 - 4\mu} = 100\mu\Omega$$

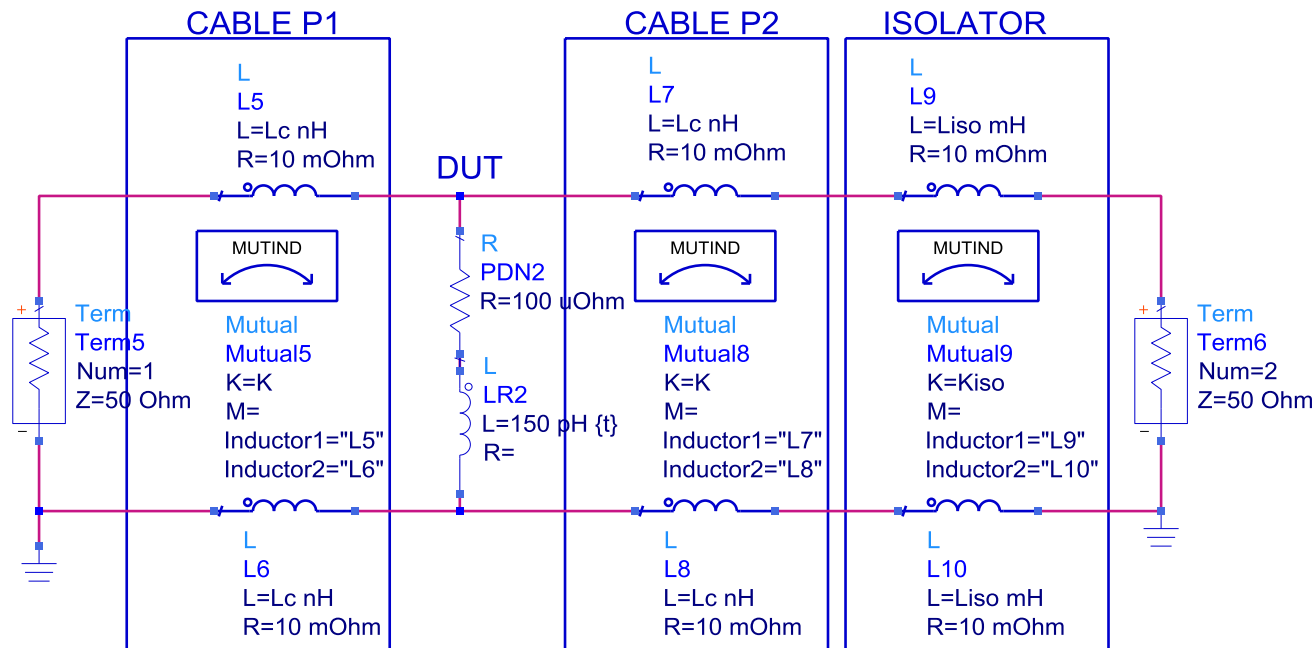




# Measurement Challenges at 100uΩ

$$S_{21} = \frac{R_{\text{shield}_1} \cdot \left(1 - \frac{1}{CMRR}\right) + DUT}{25 + R_{\text{shield}_1} \cdot \left(1 - \frac{1}{CMRR}\right) + DUT}$$

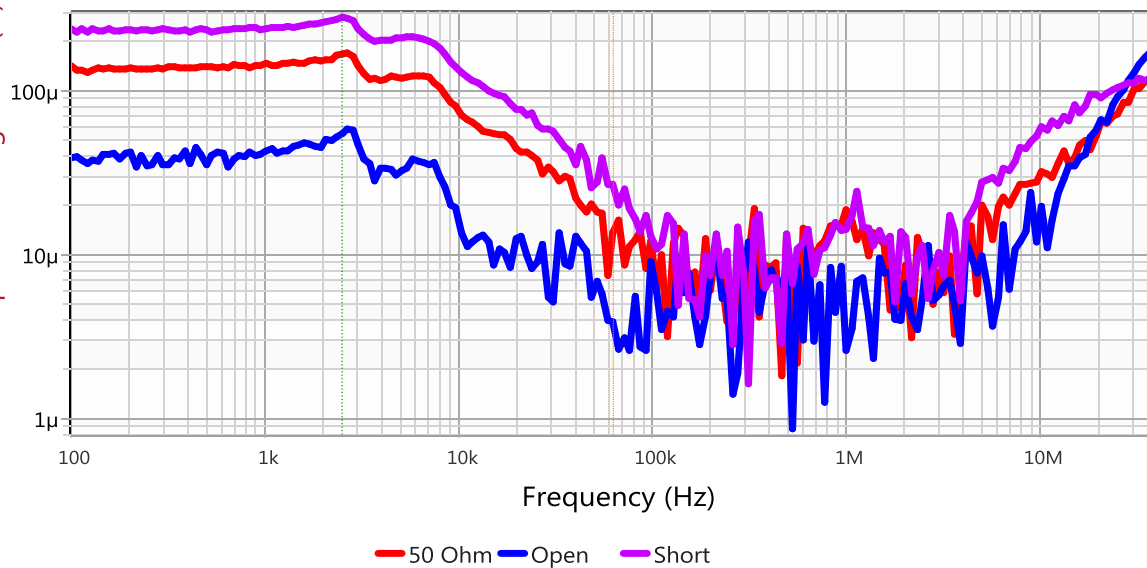
$$Error = \frac{R_{\text{shield}_1}}{CMRR}$$



# Crosstalk Issues

Near end port to port coupling due to cable loading

Trace 1: Impedance Magnitude ( $\Omega$ )



Probe tip coupling

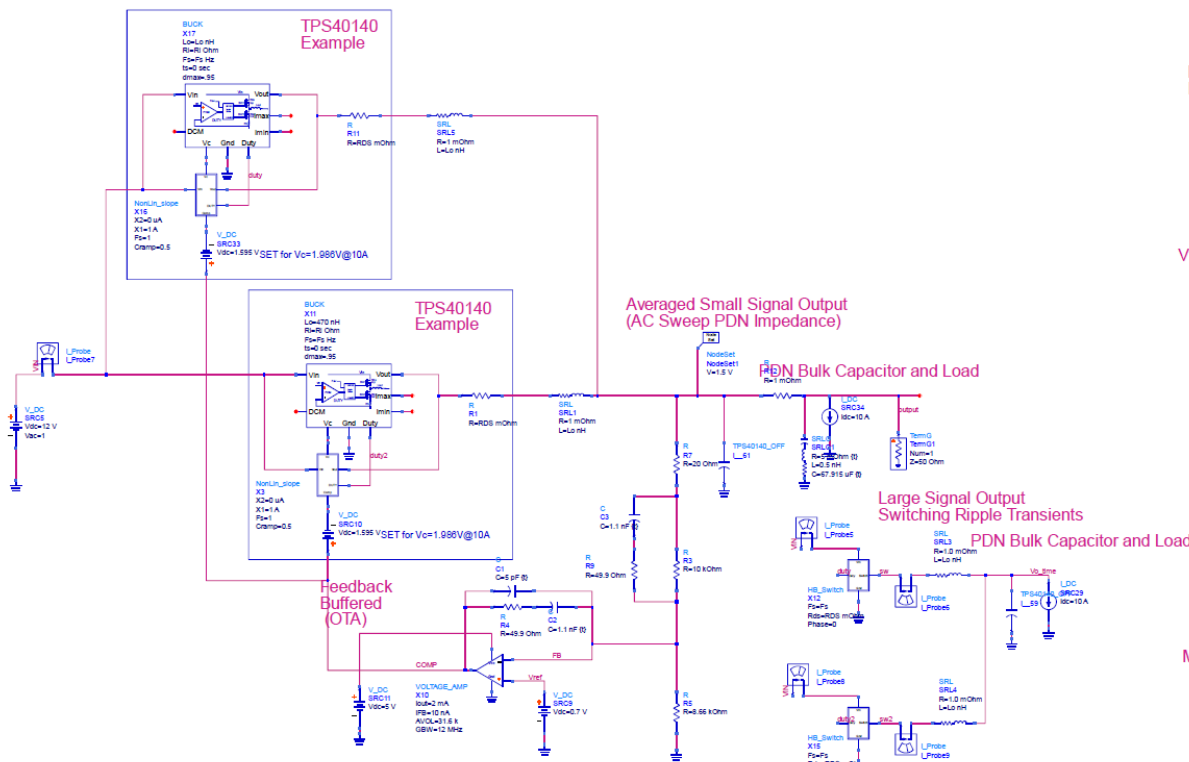


# MEASUREMENT TIPS

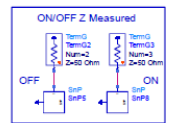
- Use ONLY SOLDERED connectors!
- Use low resistance, multi-shield cable
- Keep connections SHORT from SOURCE to DUT.
- ALWAYS check cable integrity!
- ALWAYS measure something you know, and of similar magnitude
- Probe from both sides of the board if possible
- Include quality PCB connectors if possible
- Minimize cable adapters – use metrology cable if you must use one
- Adding a **SOURCE power amplifier** will improve the signal to noise ratio



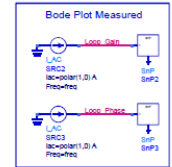
Small Signal Hybrid State Based Averaged VRM Model  
Including Discontinuous and Continuous Mode (DCM) Operation



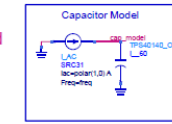
Measured Output Z  
Power OFF and Power ON



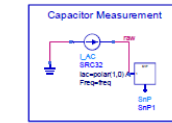
VRM Control Loop Stability



Capacitor RLC Model  
Measure Based Optimization



Measured Capacitor Impedance



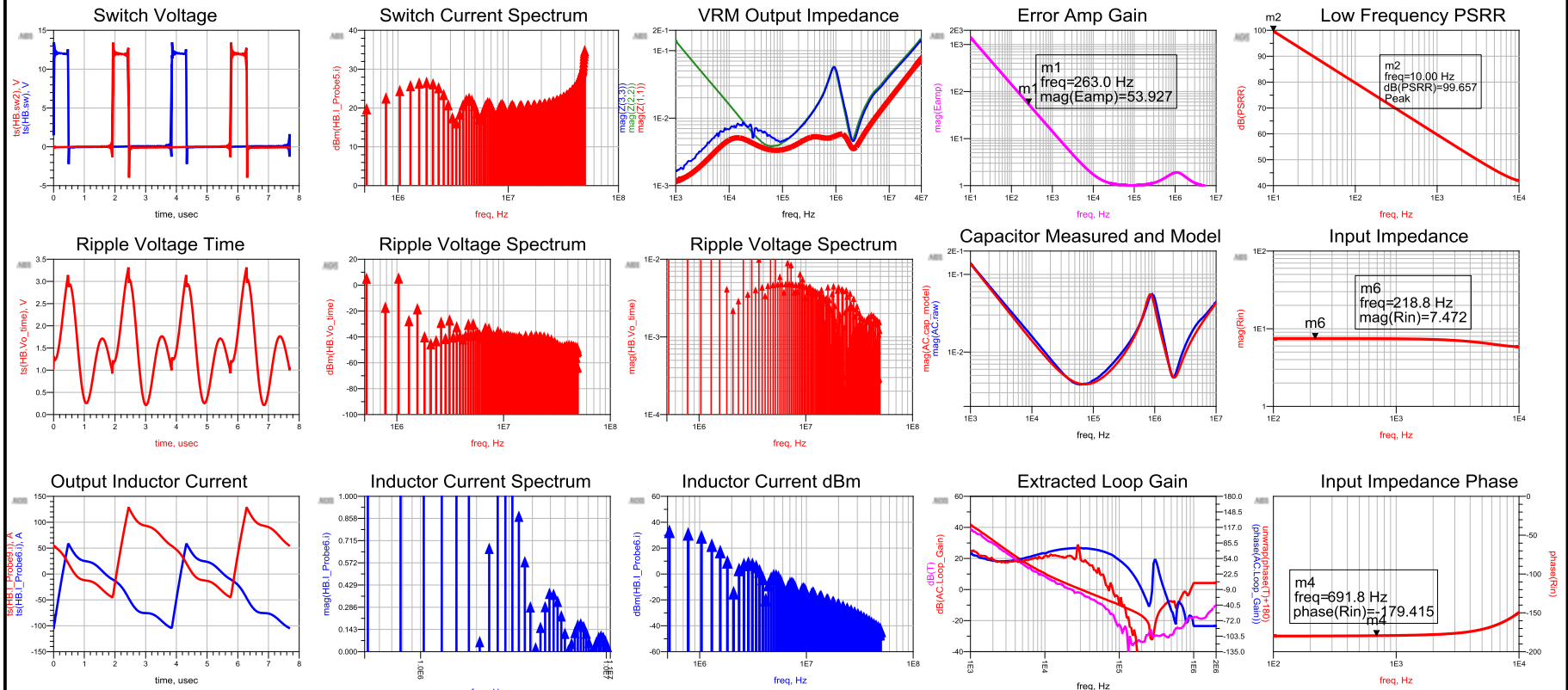
Tuned Variables for Matching  
VRM Model with Measurement

Variables	
VAR1	Freq=20 MHz
VAR2	RDS=1 B
VAR3	Rin=1 m B
VAR4	Lo=29.16 B

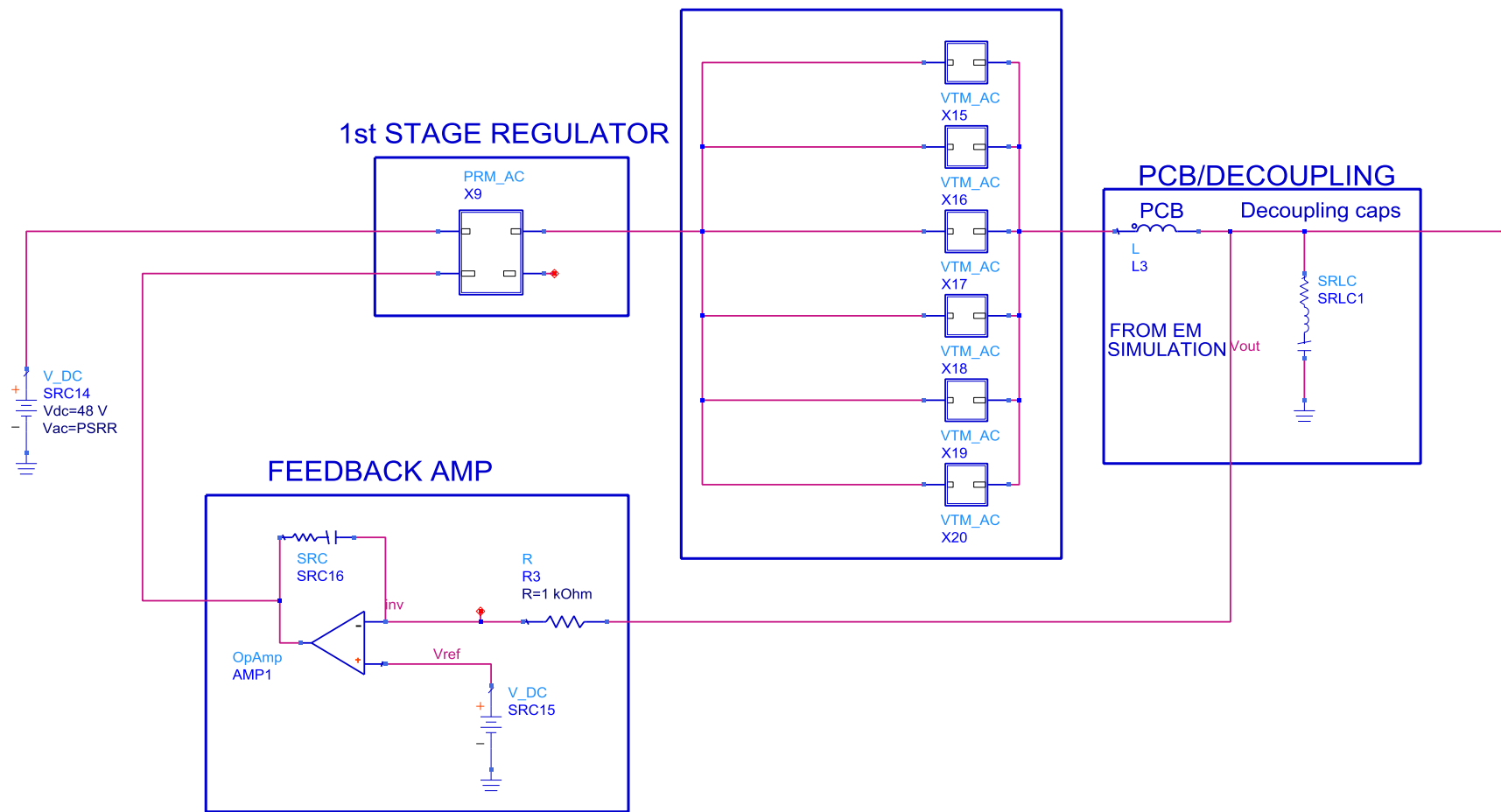
Three Separate Simulations in one Schematic

Simulation Controllers		
AC	G-PARAMETERS	HARMONIC BALANCE
IC	SP1	Harmonic Balance
AC1	SP10	HB
OS=10 Hz	Step=10 Hz	Res=1e-5
Step=10.0 MHz	Step=40 MHz	Orset=190
Step=	Step=	

## Multi-phase DC-DC Converter State Space Hybrid Model - TPS40140



#### CURRENT MULTIPLIERS

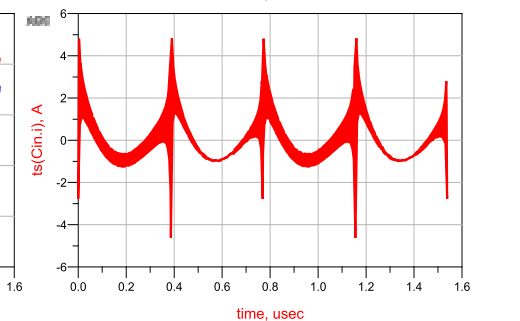
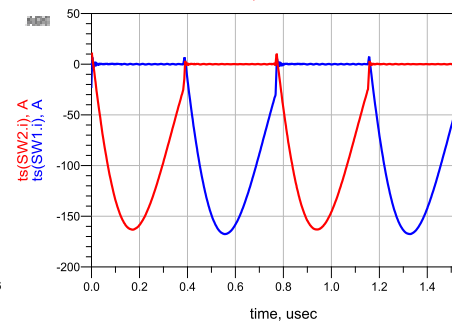
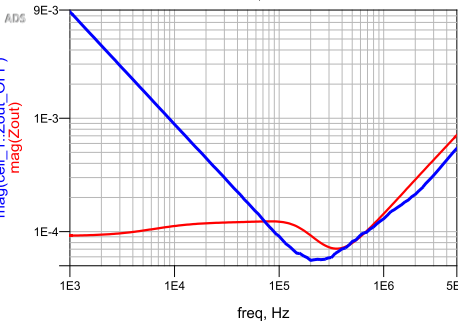
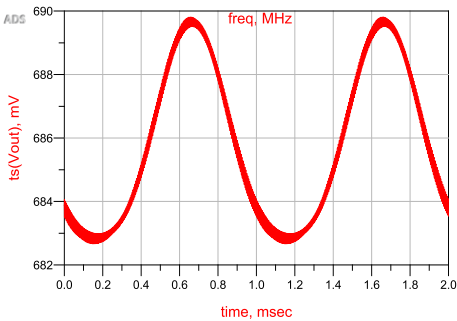
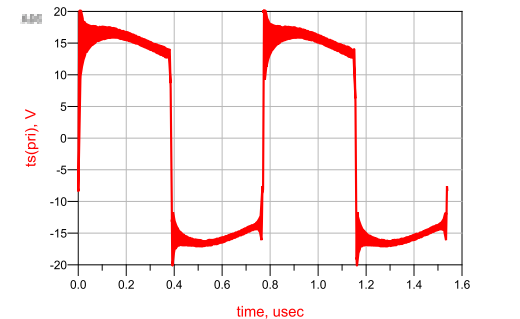
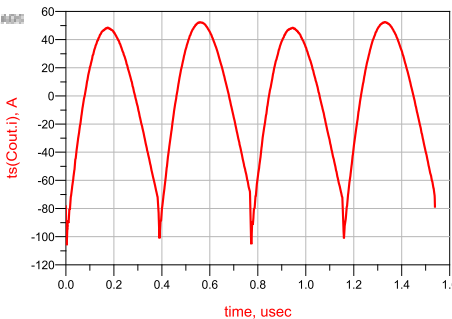
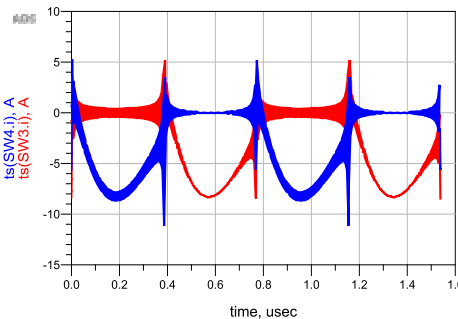
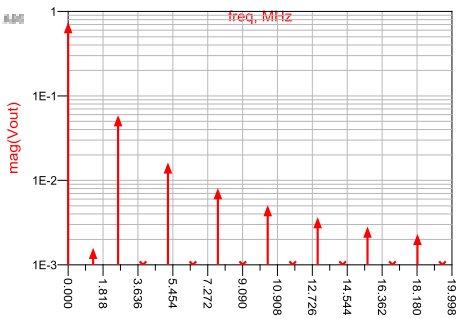
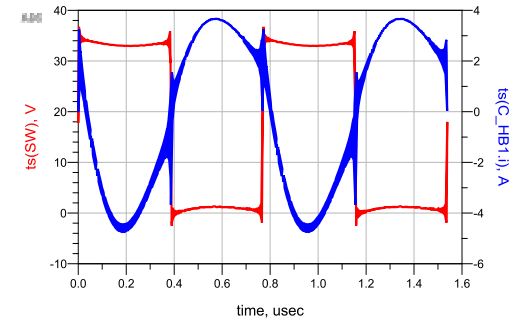
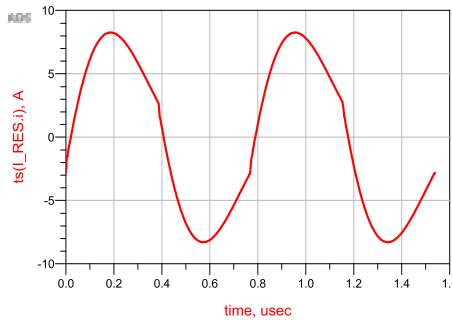
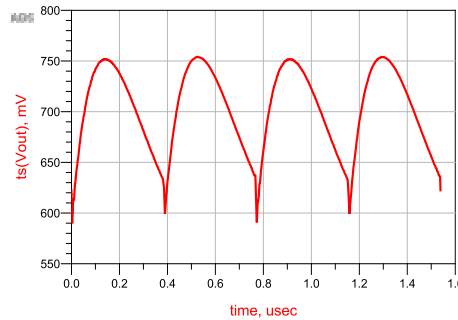
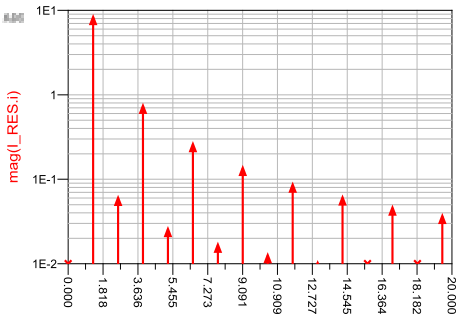




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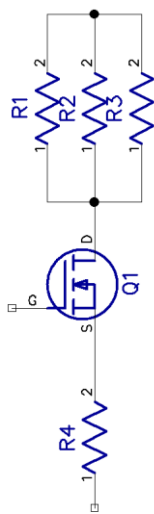
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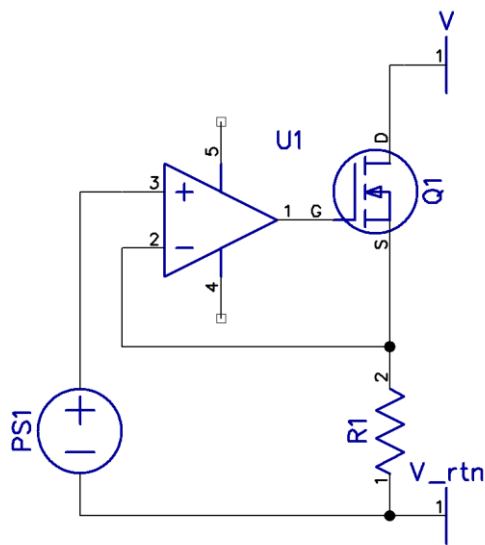


# Three (and a half) Load Testing Solutions

Slammer



Current Sink



In-socket current sink







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### SLAMMER

PROS	CONS
LOWEST COST	HIGHEST INDUCTANCE
NO STABILITY ISSUE	SLOWEST
	INTERCONNECTS

### CURRENT SINK

PROS	CONS
GENERAL SOLUTION	INTERCONNECTS
MODERATE COST	STABILITY
	HIGHER INDUCTANCE
	SLOWER SPEED

### IN SOCKET CURRENT SINK

PROS	CONS
LOWER INDUCTANCE	INTERPOSERS
HIGHER SPEED	LIMITED SPEED
PROGRAMMABILITY	COST
	COOLING

### DUT SOFTWARE

PROS	CONS
LOWEST INDUCTANCE	RISKS DUT
MIN HARDWARE	CODE DESIGN COST
HIGHEST SPEED	Indirect current
PROGRAMMABILITY	

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Is it Necessary??

It Depends!!

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# Thanks for Attending this Session!

In this session I shared

- How to create an impedance budget
- The two common design architectures
- Measurement limitations and tips to overcome them
- The biggest challenge to transient testing
- Many additional resources

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